# Extending silicon's reach: non-equilibrium doping of silicon

Mark Winkler UML colloquium 2008.10.22

## Why extend silicon's reach?



# Why extend silicon's reach?







• What we know about laser doping of silicon

- What we know about laser doping of silicon
- Structural role of dopants in infrared absorptance

- What we know about laser doping of silicon
- Structural role of dopants in infrared absorptance
- New developments and directions

## femtosecond laser doped silicon











#### structural clues new directions





#### structural clues new directions





#### structural clues







#### structural clues



#### structural clues







#### structural clues









#### structural clues









#### structural clues new directions



#### structural clues



#### structural clues







#### Laser-doping extends silicon's reach



#### Laser-doping extends silicon's reach





Hypothesis: non-equilibrium doping yields impurity band

# laser doping structural clues new directions 2<u>0 um</u>

#### laser doping structural clues ne

#### new directions



### Rough surfaces -----> Hard to characterize





 $\Delta$ 

Ο

 $\Diamond$ 

#### structural clues

#### new directions



- 10 min
- 30 min
- 100 min
- □ 6 hr
- 🗌 24 hr

diffusion length =  $\sqrt{D_i t} = f(T, t)$ 

#### structural clues



















Conclusion: diffusion is the dominant mechanism involved in deactivation of optical response



## laser doping structural clues new directions



### Rough surfaces ------ Hard to characterize

#### structural clues



#### structural clues

#### new directions

2 µm

EHT = 10.00 kV WD = 18.8 mm

Signal A = SE2 Photo No. = 5089

Date :24 Jan 2008 Time :8:54:17

77 DI N N

epoxy (used for sample preparation)

laser affected region

substrate



#### new directions

10 nm

#### Normalized Absorptance



#### New characterization techniques

secondary ion mass spectroscopy (SIMS)



#### New characterization techniques

secondary ion mass spectroscopy (SIMS)



epoxy (used for sample preparation)

laser affected region

substrate

Possible to measure optical constants chemical makeup carrier dynamics



# Isolate surface properties

device layer

buried oxide

silicon substrate



# Isolate surface properties



device layer buried oxide

silicon substrate

# Isolate surface properties

buried oxide silicon substrate

#### structural clues





#### Dopant levels from Hall measurements



#### Dopant levels from Hall measurements



#### Dopant levels from Hall measurements



structural clues

new directions

#### Conclusions

#### structural clues

#### new directions

#### Conclusions



We need to extend silicon's reach

#### structural clues

#### new directions

#### Conclusions



We need to extend silicon's reach



#### structural clues

#### new directions

#### Conclusions



We need to extend silicon's reach





Dopants diffusion governs IR response

#### structural clues

#### new directions

#### Conclusions



We need to extend silicon's reach





Dopants diffusion governs IR response



On our way to solving the puzzle!

Iaser dopingstructural cluesnew directionsAcknowledgementsEric Diebold, Albert Zhang, Jim Carey, Brian Tull

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# Thanks! Questions?

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# END OF TALK



# Why extend silicon's reach?



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# **Engineering silicon?**

- a graph showing 1st order calculation of silicon's maximum efficiency
- perhaps a picture of standard silicon cell and a black silicon on glass slide (could show again at the end of the background section)

#### After writing this talk, i think the following figures would be useful

I) a graphical representation of how we make the flat surface